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(54) **APPLYING IMPRINTING MATERIAL TO SUBSTRATES EMPLOYING ELECTROMAGNETIC FIELDS**

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(58) **Field of Classification Search** ..... None  
See application file for complete search history.

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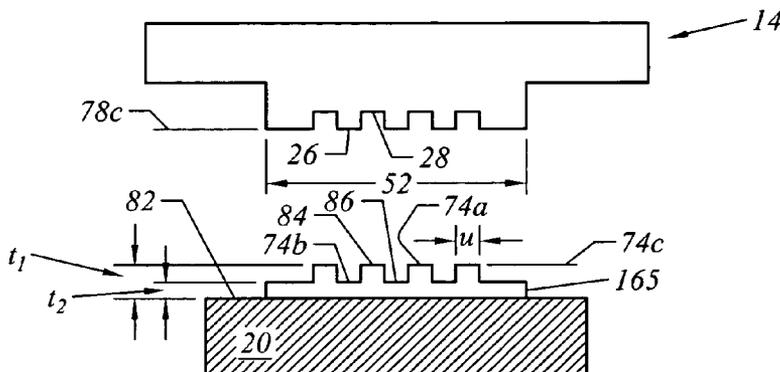
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(57) **ABSTRACT**

The present invention comprises a method for applying a liquid, such as imprinting material, to a substrate that features use of an electromagnetic field to rapidly spread the liquid over a desired portion of the substrate, while confining the same to the desired region.

**13 Claims, 5 Drawing Sheets**



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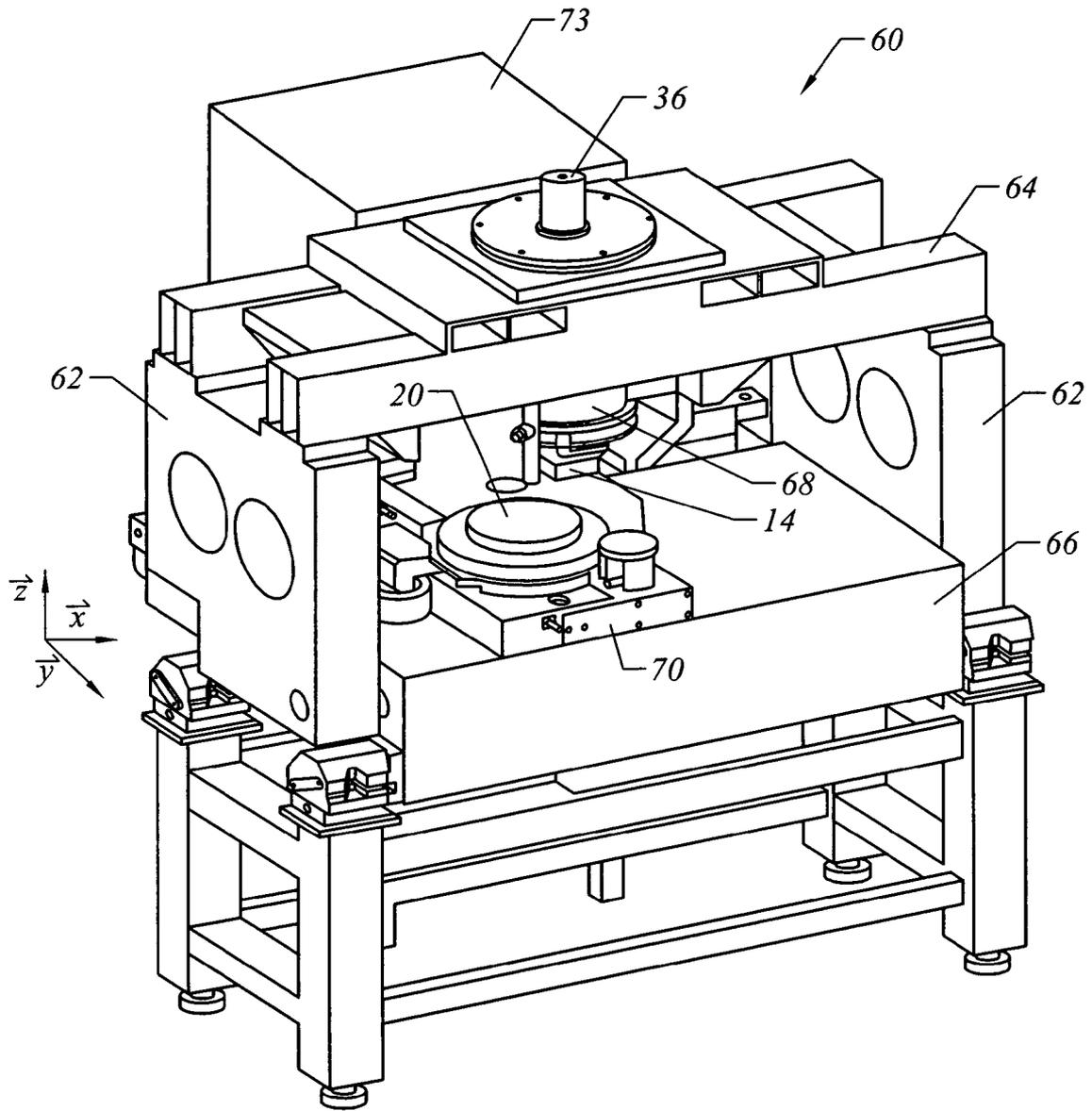


FIG. 1

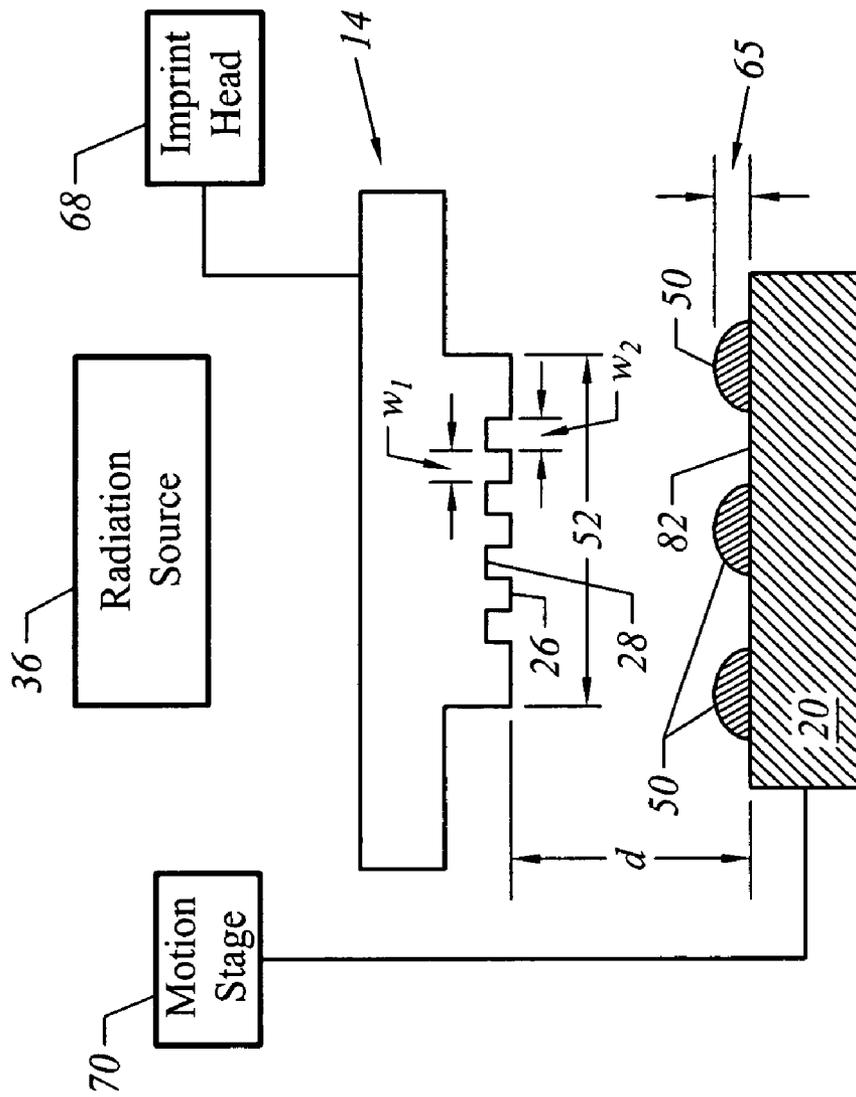
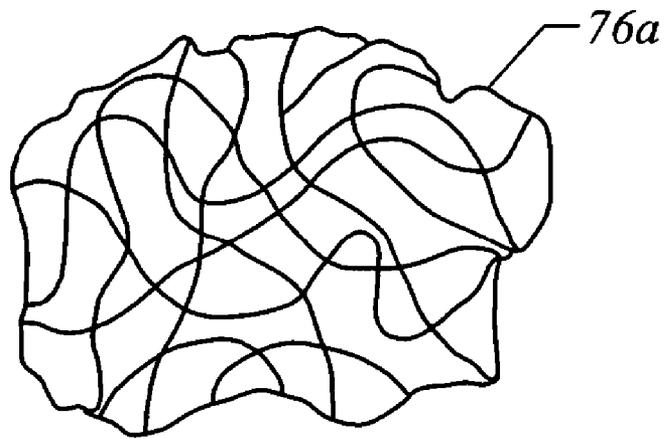
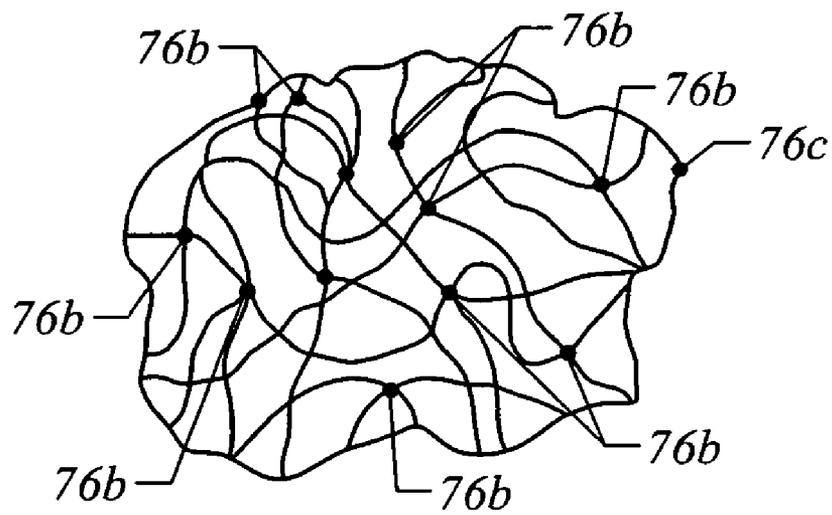


FIG. 2



*FIG. 3*



*FIG. 4*

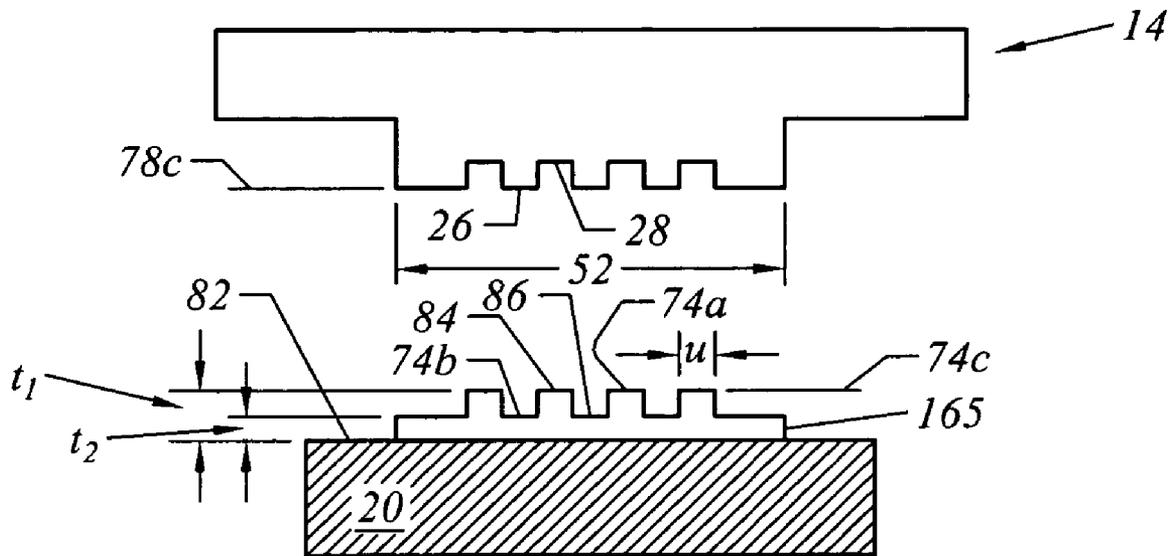


FIG. 5

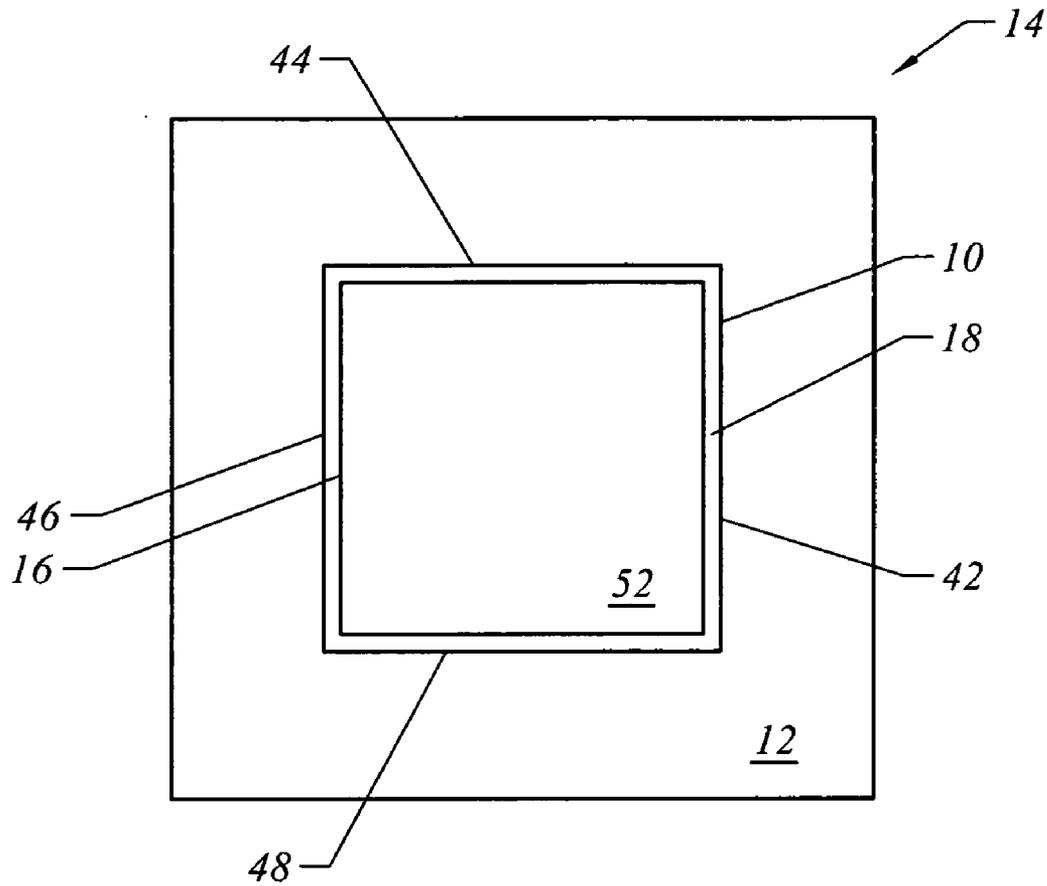


FIG. 6

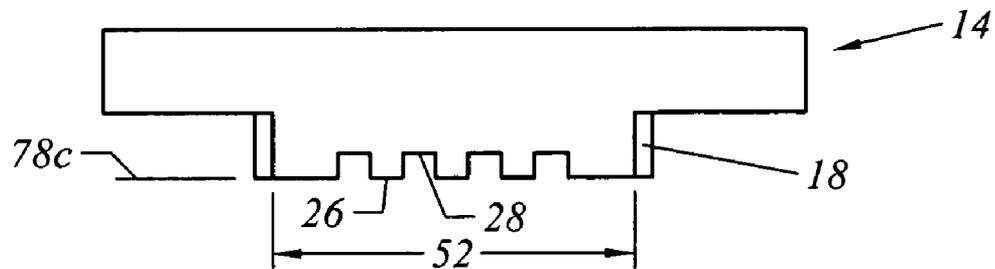


FIG. 7

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## APPLYING IMPRINTING MATERIAL TO SUBSTRATES EMPLOYING ELECTROMAGNETIC FIELDS

### BACKGROUND OF THE INVENTION

The field of the invention relates generally to micro-fabrication of structures. More particularly, the present invention is directed at the filling process of an UV curable liquid in a relief structure defined on a template.

Micro-fabrication involves the fabrication of very small structures, e.g., having features on the order of micro-meters or smaller. One area in which micro-fabrication has had a sizeable impact is in the processing of integrated circuits. As the semiconductor processing industry continues to strive for larger production yields while increasing the circuits per unit area formed on a substrate, micro-fabrication becomes increasingly important. Micro-fabrication provides greater process control while allowing increased reduction of the minimum feature dimension of the structures formed.

Optical lithography techniques are currently used in micro-fabrication. However, these methods are potentially reaching their limits in resolution. Sub-micron scale lithography has been a crucial process in the microelectronics industry. The use of sub-micron scale lithography allows manufacturers to meet the increased demand for smaller and more densely packed electronic components on chips.

An exemplary micro-fabrication technique is shown in U.S. Pat. No. 6,334,960 to Willson et al. Willson discloses a method of forming a relief image in a structure. The method includes providing a substrate having a transfer layer. The transfer layer is covered with a polymerizable fluid composition. A mold makes mechanical contact with the polymerizable fluid. The mold includes a relief structure, and the polymerizable fluid composition fills the relief structure. The polymerizable fluid composition is then subjected to conditions to solidify and to polymerize the same, forming a solidified polymeric material on the transfer layer that contains a relief structure complimentary to that of the mold. The mold is then separated from the solid polymeric material such that a replica of the relief structure in the mold is formed in the solidified polymeric material. The transfer layer and the solidified polymeric material are subjected to an environment to selectively etch the transfer layer relative to the solidified polymeric material such that a relief image is formed in the transfer layer. The time required by this technique is dependent upon, inter alia, the time the polymerizable material takes to fill the relief structure.

Thus, there is a need to provide an improved method for the filling of the relief structure with the polymerizable material.

### SUMMARY OF THE INVENTION

The present invention comprises a method for applying a liquid, such as imprinting material, to a substrate that features use of an electric field to rapidly spread the liquid over a desired region of the substrate while confining the same to the desired region. To that end, the method includes disposing the liquid between the substrate and the template; positioning the template proximate to the substrate, the template comprising a first region and a second region, lying outside of the first region; and moving the liquid over an area of the substrate in superposition with the first region by applying an electromagnetic field to the liquid. By employing an EM field to spread and confine a imprinting material to a desired area on a substrate, the time that is required to

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pattern the imprinting material is substantially reduced. By reducing the aforementioned time, the overall time efficiency of an imprint lithography process is improved. This results in increased throughput in imprint lithography.

### BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is a perspective view of a lithographic system;

FIG. 2 is a simplified elevation view of a lithographic system shown in FIG. 1;

FIG. 3 is a simplified representation of material from which an imprinting layer, shown in FIG. 2, is comprised before being polymerized and cross-linked;

FIG. 4 is a simplified representation of cross-linked polymer material into which the material shown in FIG. 3 is transformed after being subjected to radiation;

FIG. 5 is a simplified elevation view of an imprint device spaced-apart from the imprinting layer, shown in FIG. 1, after patterning of the imprinting layer;

FIG. 6 is a top view of a template comprising a template active area; and

FIG. 7 is a cross-sectional view of a template comprising a template active area.

### DETAILED DESCRIPTION OF THE INVENTION

Described below is a broad overview of an imprint lithography process. FIG. 1 depicts a lithographic system 60 in accordance with one embodiment of the present invention that includes a pair of spaced-apart bridge supports 62 having a bridge 64 and a stage support 66 extending therebetween. Bridge 64 and stage support 66 are spaced-apart. Coupled to bridge 64 is an imprint head 68, which extends from bridge 64 toward stage support 66. Disposed upon stage support 66 to face imprint head 68 is a motion stage 70. Motion stage 70 is configured to move with respect to stage support 66 along X-, Y- and/or Z-axes. An exemplary motion stage device is disclosed in U.S. patent application Ser. No. 10/194,414, filed Jul. 11, 2002, entitled "Step and Repeat Imprint Lithography Systems," assigned to the assignee of the present invention, and which is incorporated by reference herein in its entirety. A radiation source 36 is coupled to lithographic system 60 to impinge actinic radiation upon motion stage 70. As shown, radiation source 36 is coupled to bridge 64 and includes a power generator 73 connected to radiation source 36.

Referring to both FIGS. 1 and 2, connected to imprint head 68 is a template 14 having a template active area 52 thereon. Template active area 52 includes a plurality of features defined by a plurality of spaced-apart protrusions 26 and recesses 28. The plurality of features defines a relief structure that is to be transferred into a substrate 20 positioned on motion stage 70. Substrate 20 may comprise a bare wafer or a wafer with one or more layers disposed thereon, such as a planarization layer, as discussed in U.S. patent application Ser. No. 10/318,319, filed Dec. 12, 2002 and entitled "Planarization Composition And Method Patterning A Substrate Using The Same," which is incorporated by reference in its entirety herein. Imprint head 68 is adapted to move along X-, Y- and/or Z-axes. As a result, by movement of imprint head 68, motion stage 70 or both, distance "d" between template active area 52 and substrate 20 is varied. In this manner, the features on template active area 52 may be imprinted into a conformable region of substrate 20, discussed more fully below. Radiation source 36 is located so that template active area 52 is positioned between radia-

tion source **36** and substrate **20**. Thus, template active area **52** is fabricated from material that allows it to be substantially transparent to the radiation produced by radiation source **36**.

Referring to both FIGS. **2** and **3**, a conformable region, such as an imprinting layer **65**, is disposed on a portion of a surface **82** that presents a substantially planar profile. It should be understood that the conformable region may be formed using any known technique to produce conformable material, such as a hot embossing process disclosed in U.S. Pat. No. 5,772,905 to Chou, which is incorporated by reference in its entirety herein, or a laser assisted direct imprinting (LADI) process of the type described by Chou et al. in "Ultrafast and Direct Imprint of Nanostructures in Silicon," Nature, Col. 417, pp. 835-837, June 2002.

In the present embodiment, however, conformable region consists of imprinting layer **65** being deposited as a plurality of spaced-apart discrete droplets **50** of material **76a** on substrate **20**, that may be deposited in any pattern desired, e.g., periodic, aperiodic and the like. Further, droplets **50** may have identical volumes and geometries or may have differing volumes and geometries. An exemplary system for depositing droplets **50** is disclosed in U.S. patent application Ser. No. 10/191,749, filed Jul. 9, 2002, entitled "System and Method for Dispensing Liquids," assigned to the assignee of the present invention, and which is incorporated by reference herein in its entirety. Imprinting layer **65** is formed from material **76a** that may be selectively polymerized and cross-linked to record the original pattern therein, defining a recorded pattern. Material **76a** is shown in FIG. **4** as being cross-linked at points **76b**, forming cross-linked polymer material **76c**.

Referring to FIGS. **2**, **3** and **5**, the pattern recorded in imprinting layer **65** is produced, in part, by mechanical contact with template active area **52**. To that end, imprint head **68** reduces the distance "d" to allow imprinting layer **65** to come into mechanical contact with template active area **52**, spreading droplets **50** so as to form imprinting layer **65** with a contiguous formation of material **76a** over surface **82**. In one embodiment, distance "d" is reduced to allow sub-portions **74a** of imprinting layer **65** to ingress into and fill recesses **28**.

To facilitate filling of recesses **28**, material **76a**, typically an organic monomer, is provided with the requisite properties to completely fill recesses **28** while covering surface **82** with a contiguous formation of material **76a**. An exemplary embodiment of material **76a** is disclosed in U.S. patent application Ser. No. 10/463,396, filed Jun. 16, 2003, and entitled "Method to Reduce Adhesion Between a Conformable Region and a Pattern of a Mold," which is incorporated by reference in its entirety herein. In the present embodiment, sub-portions **74b** of imprinting layer **65** in superimposition with protrusions **26** remain after the desired, usually minimum, distance "d" has been reached, leaving sub-portions **74a** with a thickness  $t_1$  and sub-portions **74b** with a thickness  $t_2$ . Thicknesses " $t_1$ " and " $t_2$ " may be any thickness desired, dependent upon the application. Typically,  $t_1$  is selected so as to be no greater than twice the width  $u$  of sub-portions **74a**, i.e.,  $t_1 < 2u$ , shown more clearly in FIG. **5**. Embodiments presented herein provide a method for confining material **76a** to a desired region on substrate **20**, wherein the desired region is determined to be in superposition with template active region **52**.

Referring to FIGS. **2**, **3** and **4**, after a desired distance "d" has been reached, radiation source **36** produces actinic radiation that polymerizes and cross-links material **76a**, forming polymer material **76c** in which a substantial portion

thereof is cross-linked. As a result, material **76a** transforms to polymer material **76c**, which is a solid, forming an imprinting layer **165**, shown in FIG. **5**. Specifically, polymer material **76c** is solidified to provide a side **74c** of imprinting layer **165** with a shape conforming to a shape of a surface **78c** of template active area **52**, with imprinting layer **165** having protrusions **84** and recesses **86**. After imprinting layer **165** is transformed to consist of polymer material **76c**, shown in FIG. **4**, imprint head **68**, shown in FIG. **2**, is moved to increase distance "d" so that template active area **52** and imprinting layer **165** are spaced-apart.

Referring to FIG. **5**, additional processing may be employed to complete the patterning of substrate **20**. For example, substrate **20** and imprinting layer **165** may be etched to transfer the pattern of imprinting layer **165** into substrate **20**, providing a patterned surface (not shown). To facilitate etching, the material from which imprinting layer **165** is formed may be varied to define a relative etch rate with respect to substrate **20**, as desired.

To that end, imprinting layer **165** may be provided with an etch differential with respect to photo-resist material (not shown) selectively disposed thereon. The photo-resist material (not shown) may be provided to further pattern imprinting layer **165**, using known techniques. Any etch process may be employed, dependent upon the etch rate desired and the underlying constituents that form substrate **20** and imprinting layer **165**. Exemplary etch processes may include plasma etching, reactive ion etching, chemical wet etching and the like.

Referring to both FIGS. **1** and **2**, an exemplary radiation source **36** may produce ultraviolet radiation; however, any known radiation source may be employed. The selection of radiation employed to initiate the polymerization of the material in imprinting layer **65** is known to one skilled in the art and typically depends on the specific application which is desired. Furthermore, the plurality of features on template active area **52** are shown as recesses **28** extending along a direction parallel to protrusions **26** that provide a cross-section of template active area **52** with a shape of a battlement. However, recesses **28** and protrusions **26** may correspond to virtually any feature required to create an integrated circuit and may be as small as a few tenths of nanometers.

Referring to FIGS. **1**, **2** and **5**, the pattern produced by the present patterning technique may be transferred into substrate **20** to provide features having aspect ratios as great as 30:1. To that end, one embodiment of template active area **52** has recesses **28** defining an aspect ratio in a range of 1:1 to 10:1. Specifically, protrusions **26** have a width  $W1$  in a range of about 10 nm to about 5000  $\mu\text{m}$ , and recesses **28** have a width  $W2$  in a range of 10 nm to about 5000  $\mu\text{m}$ . As a result, template active area **52** and/or template **14**, may be formed from various conventional materials, such as, but not limited to, fused-silica, quartz, silicon, organic polymers, siloxane polymers, borosilicate glass, fluorocarbon polymers, metal, hardened sapphire and the like.

Referring to FIGS. **3**, **4** and **5**, an important requirement in obtaining accurate reproduction of template active area **52** in polymer material **76c** is ensuring that material **76a** completely spreads over a region of substrate **20** in superimposition with active area **52** in a time efficient manner. To that end, template **14** is configured to apply an electromagnetic field to material **76a** so that the same may be attracted to a perimeter of a region of substrate **20** in superimposition with active area **52**, while being confined to that region. To

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that end, template **14** includes a conducting region **18** to facilitate generation of an EM field, shown more clearly in FIGS. **6** and **7**.

Referring to both FIGS. **6** and **7**, conducting region **18** substantially surrounds a perimeter **16** of template active area **52** of template **14**. Inclusion of conducting region **18** with template **14** facilitates rapid spreading of imprinting material **76a** over the region of substrate **20** in superimposition with template active area **52** and maintains the absence of material **76a** in regions of substrate **20** not in superimposition with template active area **52**. This results from the application of a voltage to conducting region **18** which creates an EM field produced. To that end, conducting region **18** is connected to a voltage source (not shown), desired to generate the EM field.

Conducting region may be formed from any suitable material, such as Indium Tin Oxide (ITO). ITO is transparent to visible and UV light and may be patterned using high-resolution e-beam lithography.

While the invention has been described with references to various illustrative embodiments, the description is not intended to be construed in a limiting sense. Various modifications and combinations of the illustrative embodiments, as well as other embodiments of the invention, will be apparent to persons skilled in the art upon reference to the description. It is, therefore, intended that the appended claims encompass any such modifications or embodiments.

What is claimed is:

**1.** A method of applying a liquid to a substrate the method comprising the steps of:

disposing the liquid between the substrate and a template as a plurality of spaced-apart droplets;

positioning the template proximate to the substrate, the template comprising a first region and a second region, lying outside of a perimeter of the first region, the template further comprising electrodes positioned around the perimeter of the first region; and

moving the liquid to form a contiguous layer of said liquid over an area of the substrate in superposition with the first region by exposing said liquid to an electromagnetic field generated by said electrodes.

**2.** The method as recited in claim **1**, wherein moving further includes moving the liquid over the area and towards the perimeter of the first region while preventing the liquid from moving to portions of the substrate beyond the perimeter of the first region into the second region.

**3.** The method as recited in claim **1**, wherein the first region further includes patterned features comprising protrusions and recesses, wherein moving further includes compressing the liquid with the first region and solidifying the liquid to form a pattern conformal to the patterned features.

**4.** The method as recited in claim **1**, wherein the first region further includes a smooth surface, wherein moving further includes compressing the liquid with the first region and solidifying the liquid to form a pattern conformal to the smooth surface.

**5.** A method of applying a liquid to a substrate employing a template, the method comprising:

disposing the liquid on a surface of the substrate as a plurality of spaced-apart droplets;

positioning the template proximate to the liquid, the template comprising a first region, a second region and a conducting layer, a first portion of which surrounds the first region; and

generating, with the conducting layer of the template, an electromagnetic field to move the liquid to form a

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contiguous layer of said liquid over an area of the substrate in superimposition with the first region, while confining the liquid to be absent from portions of the substrate in superimposition with regions of the template outside of the first region.

**6.** The method as recited in claim **5**, wherein the first region further includes patterned features comprising protrusions and recesses, wherein positioning further includes compressing the liquid with the first region and solidifying the liquid to form a pattern conformal to the patterned features.

**7.** The method as recited in claim **6**, wherein disposing further includes depositing, on the substrate, the liquid as a plurality of spaced-apart droplets and generating the electric field further includes moving portions of the liquid in a subset of the plurality of spaced-apart droplets toward a perimeter of the first region.

**8.** The method as recited in claim **7** further includes, before generating, spreading liquid associated with the spaced-apart plurality of droplets by compressing the plurality of spaced-apart droplets between the template and the substrate.

**9.** A method of applying a liquid to a substrate employing a template, the method comprising:

disposing the liquid on a surface of the substrate;

positioning the template proximate to the liquid, the template comprising a first region, a second region surrounding a perimeter of the first region, and a conducting layer positioned around the perimeter of said first region; and

generating, with the conducting layer of the template, an electromagnetic field to move the liquid over an area of the substrate in superimposition with the first region towards the perimeter of the first region and not beyond the perimeter into the surrounding second region.

**10.** The method as recited in claim **9**, wherein the first region further includes patterned features comprising protrusions and recesses, wherein positioning further includes compressing the liquid with the first region and solidifying the liquid to form a pattern conformal to the patterned features.

**11.** A method of applying a liquid to a substrate employing a template, the method comprising the steps of:

disposing the liquid between the substrate and the template;

positioning the template proximate to the substrate, the template comprising an active region and an inactive region, lying outside of the active region, wherein the active region includes patterned features of a mold comprising protrusions and recesses, and the inactive region does not include patterned features, the template further comprising a ring of conductors positioned around a perimeter surrounding the active region; and

completely spreading the liquid over an area of the substrate in superposition with the active region by exposing said liquid to an electromagnetic field generated by the ring of conductors so that the liquid approaches but does not cross over the perimeter surrounding the active region.

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12. The method as recited in claim 11, wherein the active region further includes patterned features comprising protrusions and recesses, wherein moving further includes compressing the liquid with the active region and solidifying the liquid to form a pattern conformal to the patterned features. 5

13. The method as recited in claim 11, wherein disposing further includes depositing, on the substrate, the liquid as a

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plurality of spaced-apart droplets, wherein moving further includes moving a portion of the liquid in a subset of the plurality of spaced-apart droplets toward the perimeter of the active region.

\* \* \* \* \*